Unit: mm

TOSHIBA INSULATED GATE BIPOLAR TRANSISTOR SILICON N CHANNEL IGBT

# GT60M303

#### HIGH POWER SWITCHING APPLICATIONS

Fourth generation IGBT

• FRD included between emitter and collector

• Enhancement mode type

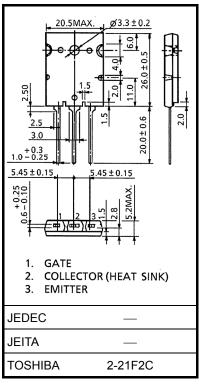
• High speed  $I_{GBT}$ :  $t_f = 0.25 \mu s$  (TYP.)

FRD :  $t_{rr} = 0.7 \mu s$  (TYP.)

• Low saturation voltage :  $V_{CE (sat)} = 2.1V (TYP.)$ 

### **ABSOLUTE MAXIMUM RATINGS (Ta = 25°C)**

CHARACTERISTIC		SYMBOL	RATING	UNIT	
Collector-Emitter Voltage		V <sub>CES</sub>	900	V	
Gate-Emitter Voltage		V <sub>GES</sub>	±25	V	
Collector Current	DC	IC	60	Α	
	1ms	I <sub>CP</sub>	120		
Emitter-Collector Foward Current	DC	I <sub>ECF</sub>	15	А	
	1ms	IECFP	120		
Collector Power Dissipation (Tc = 25°C)		P <sub>C</sub>	170	W	
Junction Temperature		Tj	150	°C	
Storage Temperature Range		T <sub>stg</sub>	-55~150	°C	
Screw Torque		_	0.8	N·m	

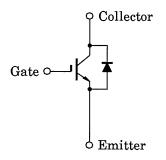


Weight: 9.75 g (typ.)

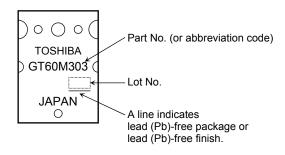
Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **EQUIVALENT CIRCUIT**

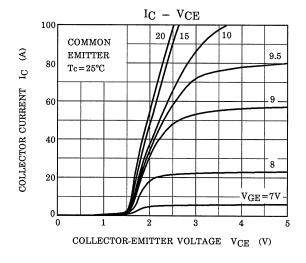


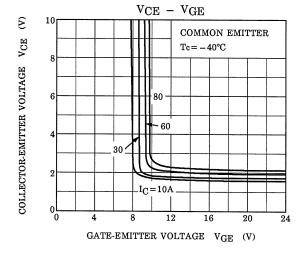
#### **MARKING**

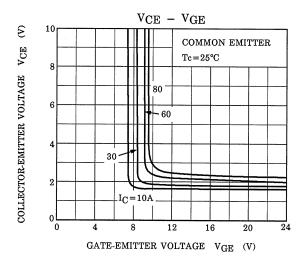


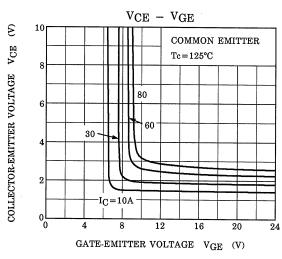
## ELECTRICAL CHARACTERISTICS (Ta = 25°C)

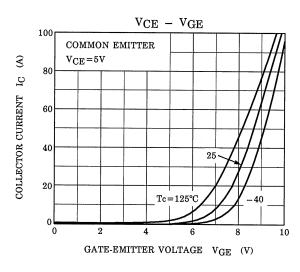
CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN	TYP.	MAX	UNIT
Gate Leakage Current		I <sub>GES</sub>	V <sub>GE</sub> = ±25V, V <sub>CE</sub> = 0	_	_	±500	nA
Collector Cut-off Current		I <sub>CES</sub>	V <sub>CE</sub> = 900V, V <sub>GE</sub> = 0	_	_	1.0	mA
Gate-Emitter Cut-off Voltage		V <sub>GE</sub> (OFF)	I <sub>C</sub> = 60mA, V <sub>CE</sub> = 5V	3.0	_	6.0	V
Collector-Emitter Saturation Voltage		V <sub>CE</sub> (sat) (1)	I <sub>C</sub> = 10A, V <sub>GE</sub> = 15V	_	1.6	2.2	V
Collector-Emitter Saturation Voltage		V <sub>CE</sub> (sat) (2)	I <sub>C</sub> = 60A, V <sub>GE</sub> = 15V	_	2.1	2.7	V
Input Capacitance		C <sub>ies</sub>	V <sub>CE</sub> = 10V, V <sub>GE</sub> = 0, f = 1MHz	_	3800	_	pF
Switching Time	Rise Time	t <sub>r</sub>	15V 0 51Ω 600V	_	0.35	0.60	- µs
	Turn-On Time	t <sub>on</sub>		_	0.46	0.75	
	Fall Time	t <sub>f</sub>		_	0.25	0.40	
	Turn-Off Time	t <sub>off</sub>		_	0.60	0.70	
Emitter-Collector Forward Voltage		V <sub>ECF</sub>	I <sub>EC</sub> = 15A, V <sub>GE</sub> = 0	_	1.5	2.0	V
Reverse Recovery Time		t <sub>rr</sub>	$I_F = 15A$ , $V_{GE} = 0$ di / dt = -20A / $\mu$ s	_	0.7	2.5	μs
Thermal Resistance		R <sub>th (j-c)</sub>	IGBT	_	_	0.74	°C / W
Thermal Resistance		R <sub>th (j-c)</sub>	Diode	_	_	4.0	°C / W

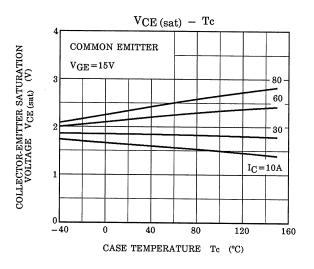


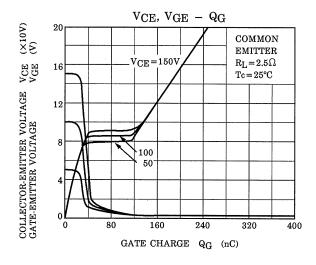


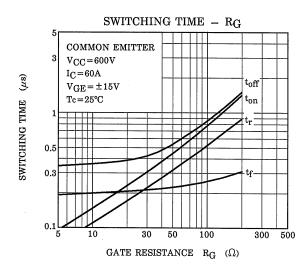


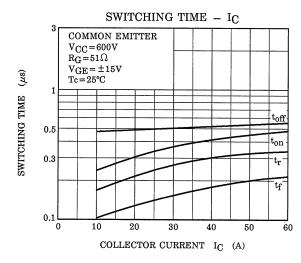


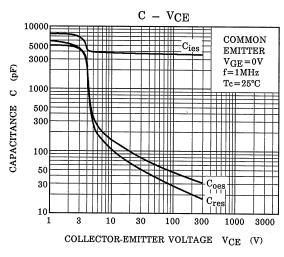


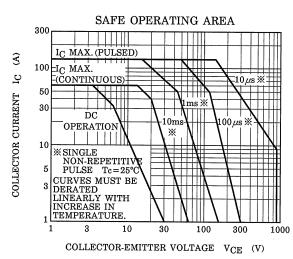


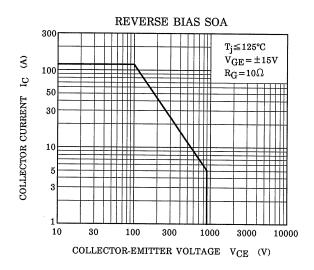


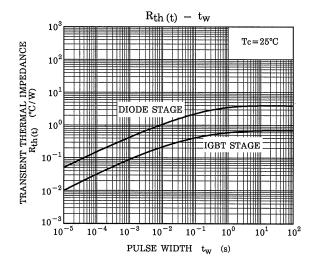


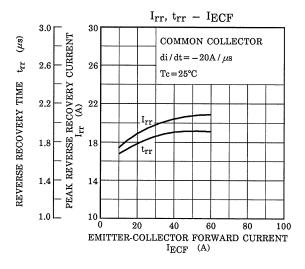


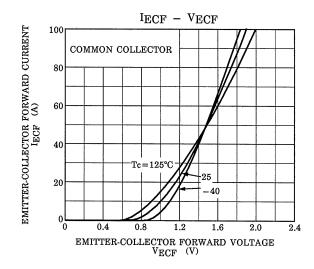


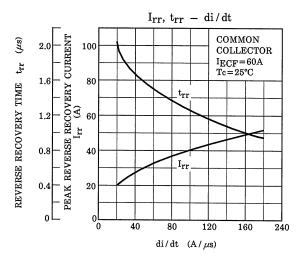












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